S	e	â	1	7	C	į	f	7	i	V	()	ť	(е	S	;



Application/Control No.	Applicant(s)/Patent under Reexamination							
10/531,467	KAWAI ET AL.							
Examiner	Art Unit							
Michael Bernshteyn	1713							

	SEAR	CHED	
	02/110		
Class	Subclass	Date	Examiner
526	323.2	2/10/2006	МВ
526	329.7	2/10/2006	МВ

INT	INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner				
		- 10					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
EAST (USPAT, JPO, EPO,DERWENT, PREGRANT)	2/10/2006	МВ			
PALM, eDAN, Inventors and Assignee search update	2/10/2006	МВ			
NPL	2/10/2006	МВ			